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Parent Case Text

CROSS REFERENCE TO CO-PENDING APPLICATION

Applicant claims the benefit of the priority filing date of Nov. 27, 2001 of U.S. Provisional Patent Application S.No. 60/333,555, now abandoned, the contents of which are incorporated herein in its entirety.

Claims

What is claimed is:

1. A method for forming a slot in a first surface of an article having first and second opposed surfaces, the method comprising the steps of: generating a scoring light beam; using the beam to form a slot in the article of a predetermined depth in the first surface; and confocally determining the remaining thickness in the article between a bottom of the slot and the opposed second surface of the article.
2. The method of claim 1 further comprising the step of: controlling the scoring beam in response to the sensed remaining thickness in order to obtain a predetermined constant thickness along an entire length of the slot.
3. The method of claim 1 wherein the step of confocally determining the remaining thickness in the article comprises the steps of: generating a detection light beam; and directing the detection light beam into the slot and confocally determining the intensity of light reflected from the bottom of the slot with respect to a focal plane at the predetermined depth of the bottom of the slot to provide an output proportional to the remaining thickness in the article between the bottom of the slot and the opposed second surface of the article.

weakened seamless panel edge.

It is imperative for appearance as well as proper timed deployment of the airbag during a collision, that the scored slot be of a constant and appropriate depth along the entire pre-weakened edge of the panel. If the slot is too deep, the slot may be visible from the exterior side of the instrument panel. At the same time, any force exerted on the panel from the exterior side of the instrument panel could break the remaining portion of the scored edge.

Alternately, if the scored slot is too shallow, there may not be sufficient force generated by the airbag during deployment to break through the pre-weakened edge along the entire extent of the pre-weakened edge. This could interfere with the proper timed full deployment of the airbag.

In order to insure the constant and appropriate depth slot, various measurement techniques have been employed, including laser triangulation, ultrasonic measurement, and light transmission through remaining material at the score slot.

While all of these measurement techniques have advantages and disadvantages, the disadvantages are amplified when it is desirable to mount the typically thin outer skin of the instrument panel on one or more backing layers and a rigid substrate. The pre-weakened edge must be formed through all of the substrate and backing layers and into the predetermined depth in the instrument panel skin. Measurement of the slot or hole depth when a backing and/or substrate is employed is much more difficult due to the depth of the slot or hole which blocks a portion of the light to and from the sensor making it difficult to accurately measure the exact depth of the slot or hole. In the light transmission method, the remaining thickness of material in the instrument panel skin must be thin enough to let enough light pass through for measurement. Sometimes the remaining thickness is thinner than desired. In addition, the light transmission method is dependent upon the optical properties of the material. When the manufacture changes material, it must recalibrate the measurement process and adjust the scoring process thereby increasing cost and production downtime. The ultrasound measurement method lacks measurement precision.

Thus, it would be desirable to provide a measurement apparatus and method used with a laser scoring process to accurately measure the depth of the score slot or holes despite any additional backing layers and substrates mounted on the outer skin. It would also be desirable to provide a slot measurement apparatus and method which provides accurate slot depth measurement despite any exterior surface irregularities in the outer layer or skin.

SUMMARY

The present invention is an apparatus and method for forming a slot of a predetermined configuration in an article, with the remaining depth between the bottom of the slot and the opposed surface of the article held constant along the entirety of the slot despite any surface dimensional variations in the article.

In one aspect, the present inventive method includes the steps of: generating a scoring light beam; using the scoring light beam to form a slot in the article of a predetermined depth in the first surface; and confocally determining the remaining thickness in the article between a bottom of the slot and the opposed second surface of the article.

In another aspect of the invention, the inventive apparatus includes a source for directing a scoring laser beam onto a first surface of an article to form a slot in the article, and means for confocally sensing the remaining thickness in the article between a bottom of the slot formed by the beam and the other of the first and second surfaces of the article.

The apparatus and method of the present invention uniquely and efficiently provides a constant remaining thickness in an article between the bottom of a scored slot in the opposed surface of the article along the entirety of the slot despite any dimensional surface variations in the article. The confocal slot depth detection of the present apparatus and method enables the depth of the slot to be determined in real time to accurately control the application of a scoring laser beam during formation of each point along the entirety of the slot.

BRIEF DESCRIPTION OF THE DRAWING

The various features, advantages and other uses of the present invention will become more apparent by referring to the following detailed description and drawing in which:

FIG. 1 is a pictorial representation of a confocal optical system for detecting light intensity at a confocal plane;

FIG. 2A is a graph depicting light intensity versus the distance of the confocal plane shown in FIG. 1 from a reference plane;

FIG. 2B is a graph depicting an alternate technique for determining the confocal position;

FIG. 3 is a pictorial representation of a laser score slot formed in a multi-layer instrument panel assembly;

FIG. 4 is a pictorial representation showing the use of another aspect of the present invention in measuring laser score slots in material of varying thickness;

FIG. 5 is a pictorial representation of a first aspect of a confocal laser scoring measurement apparatus according to the present invention; and

FIG. 6 is a pictorial representation of a confocal laser score measurement apparatus according to another aspect of the present invention.

DETAILED DESCRIPTION

Confocal Optic Principals

FIG. 1 depicts the principals of a confocal optical system. Confocal optics or imaging is used in microscopes to obtain fine lateral and axial resolutions and layer imaging. As shown in FIG. 1, a light beam 10 from a light source, not shown, which may be a laser beam generated from a laser, is directed toward a beam splitter 17. The light beam passes through the beam splitter 17 toward a first objective lens 16. The first lens 16 focuses the light beam 10 onto a reflective surface or focal plane denoted generally by reference number 18.

Light is reflected off of the surface 18 back through the reflective surface of the beam splitter 17. This light is reflected by the beam splitter 17 through a second detector lens 20 spaced from the beam splitter 17 and from a light intensity detector 24. The focused light passes through a pinhole 22 in a member 23 onto the detector 24 which provides an output signal indicative of the detected light intensity.

The distance between the pin hole 22 and the beam splitter 17 is selected such that only substantially all of the light reflected off of the surface 18 will be focused and able to pass through the pinhole 22 to the detector 24. Light reflected off of other planes 1 and 2 spaced at different distances from the second lens 20 will be mostly blocked by the member 23 in which the pinhole 22 is formed.

As shown in FIG. 2A, this confocal optical concept provides a sharp increase in detected light intensity only at a certain surface spacing 18 from the first focusing lens 16. Light reflected off of the other planes 1 and 2 will be mostly blocked by the member 23 thereby providing low detected light intensities from the planes 1 and 2.

Usage of this confocal optical imaging principal enables a light intensity threshold denoted by reference number 32 in FIG. 2A to be established and used as a measurement of the position of the surface 18 from a reference point or plane. When the first lens 16 is moved in a axial direction, the focal plane or surface 18 moves accordingly in the same distance. This provides a means of focusing the beam into a different depth in a sample and thus enables inspecting features in different depths in the sample with great depth discrimination.

Another technique for determining confocal position is shown in FIG. 2B. If the optics used to focus the reflected confocal beam onto a detector are dithered or moved in an axial direction with small magnitude, the confocal point oscillates in a small magnitude relative to a pin hole in a spaced filter. This in turn causes

The probe beam 82 is reflected off of the rear surface 90 of the beam splitter 76 into the slot 38 being formed by the scoring beam 64. A portion of the probe beam 82 will be reflected out of the bottom 52 of the slot 38 and from the rear surface 90 of the first beam splitter 76 back through the focusing lens 88 where it is defocused to a parallel beam directed toward the second beam splitter 86. This portion of the reflected probe beam will pass through the second beam splitter 86 and be focused by a third focusing lens 90 through a aperture or pinhole 92 in a member or filter 94 disposed at a fixed or variable distance from a light intensity detector means 96. A movable mounting unit 95 supports the filter 94 and receives control signals from the controller 66 to vary the confocal plane as necessary. Movement of the second lens 88 or the filter 94, as described above, allows accommodation of the different locations of the confocal plane 71 in the sample 42. Further, the sample 42 can be moved in the Z direction by a motion unit 59 controlled by a motion controller 57 under the control of the controller 66. In addition, all three described means for changing the location of the confocal plane 71 can be used to provide dithering for the slope zero measurement technique described above.

When two lasers, such as the scoring laser 62 and the probe laser 80, are used, both lasers 62 and 80 need to be aligned so that the respective laser beams are collinear and overlapped on the bottom 52 of the slot 38. When moving or scanning the lasers 62 and 80, the alignment of the laser beams remains in tact. This insures that the probe beam 82 always is directed to the bottom 52 of the slot 38.

As described in the confocal imaging concept shown in FIG. 1, only the light reflected off of the confocal plane 71 impinges upon the detector elements of the detector 96, with light from other planes being substantially blocked by the member 94.

The detector 96 is capable of generating an output signal similar to that shown in FIG. 2 which measures the light intensity with respect to the distance of the confocal plane 71 from a reference plane. The detector 96 may be programmed or set up to provide an output signal 98 whenever the measured light intensity, such as that shown by reference number 26 in FIG. 2, equals or exceeds a predetermined threshold intensity 32. When the threshold 32 is met, the output signal 98 from the detector 96 to the controller 66 is an indication that the bottom 52 of the slot 38 is at a requisite distance to leave the desired amount of remaining material T.sub.R in the outer material layer or skin 40. The controller 66, upon receiving the threshold matching signal 98 from the detector 96 will generate appropriate signals to the laser controller 68 to cease generation of the scoring beam 64 at that point in the sample 42.

Digital signal processing means can be used to increase the signal-to-noise ratio of the signal 98 and, as a result, scoring depth measurement accuracy. One means would be to include a lock-in amplifier 104 between the output of the detector 96 and the controller 66 input. The laser beam 82 can be modulated at a fixed frequency F. The laser beam modulation can be done by direct modulation of the laser 80, the use of external mechanical chopper, or an acousto-optical modulator. The signal 98 is also modulated with the frequency F. When the signal 98 is fed to a lock-in amplifier, such as one commercially available from Stanford Research System, CA, or others, the amplifier 104 can pickup the frequency F signal out of any noise signal. The noise signal may come from debris, smoke, or liquid generated from the scoring process which interferes with the probe beam in or near the slot 38. Noise can also come from environmental air flows, vibrations. All such noise has a broader spectrum or other frequencies different from the modulated frequency F. By only measuring the signal with the frequency F, the effect of noise signals from all of the above sources can be greatly reduced. This enable an increase in the signal-to-noise ratio as well as an increase in the accuracy of laser scoring depth.

Other signal processing techniques can also be used to increase signal-to-noise ratio. For example, accruing multiple depth points and averaging the depth measurements of such points can be used to reduce the noise level. Applied real-time digital filtering to the signal 98 to eliminate noise in certain frequency spectrums can also be used to enhance signal level.

The motion controller 60 continues to move the laser 62 in a predetermined pattern to form the entire slot 38 so that the laser controller 68 continues to supply signals to the laser 62 to generate additional scoring beams 64 as the laser 62 traverses in a predetermined pattern across the sample 42.

As described above and shown in FIG. 4, the outer surface 44 of the sample 42 frequently has an irregular surface configuration formed by graining or other surface ornamentation. A suitable surface measurement

detector 100, such as a laser triangulation detector or sensor shown in FIG. 5, generates light beams which are reflected off of the outer surface 44 at the point of formation of the slot 38 to determine the position of the outer surface 44 with respect to a reference plane.

Alternately, the detector 100 can be a confocal measurement device, such as the confocal system 24 described above and shown in FIG. 1. The measured distances from the detector 100 are input to the controller 66 to be used in controlling the position of the lens 88 to move the focal plane 71 and, also, in controlling the generation of the scoring beam 64 by the laser 62 so as to maintain the remaining thickness $T_{sub.R}$ in the outer material layer 40 of the sample 42 constant as described above and shown in FIG. 4 by $T_{sub.R}$ and $T_{sub.R}$.

To avoid interference or cancellation, the wavelength of the probe beam 82 generated by the laser 80 should be different from the wavelength of the scoring beam 64 generated by the laser 62. For example, if the laser 62 is a carbon dioxide (CO₂) laser, the probe beam generating laser 80 should be a laser generating a different wavelength beam, such as an He-Ne, diode laser or a solid state laser.

Alternately, the lasers 62 and 80 may generate identical wavelength scoring beams 64 and probe beams 82, respectively. A phase offset, or a polarization difference, may be introduced into the probe beam 82, for example, to avoid interference with the scoring beam 64.

FIG. 6 depicts another aspect of a confocal imaging apparatus and method used to maintain a constant remaining thickness in a sample in which a scored slot 38 is formed by the laser scoring beam 64. Since certain elements are employed in both aspects shown in FIGS. 5 and 6, the same reference numbers are used to refer to the same component in both FIGS. 5 and 6. In addition, the control elements, such as the controller 66, the motion controller 60 and the laser controller 68, while used in the apparatus shown in FIG. 6, are omitted from FIG. 6 for clarity.

As shown in FIG. 6, after the actual scoring beam 64 has passed through the first lens 70 and the first beam splitter 76 and formed the slot 38 in the sample 42, a percentage of the light will be reflected off of the bottom 52 of the slot 38. This light reflects out of the sample 42 to the surface 90 of the first beam splitter 76 and is reflected through the second focusing lens 88. The second lens 88 is mounted on a movable lens mount 89 to accommodate different locations of the confocal plane 71 in the sample 42.

To avoid interference between the reflected beam and the laser beam 64, the first beam splitter 76 may be a polarization beam splitter which transmits one linear polarization totally and reflects orthogonal polarization totally. Optionally, a quarter wave plate 102 is disposed between the first beam splitter 76 and the sample 42. The quarter wave plate 102 converts the linear polarization of the beam 64 to a circular polarization and, when the circularized light is reflected back from the sample 42, the quarter wave plate 102 converts the light back to a linear polarization in the orthogonal direction. This enables the reflected light to pass to a detector 96 and not be reflected back to the laser 62.

The second lens 88 converts the de-focused reflected beam from the beam splitter 90 to a parallel beam which is focused by the third lens 90 through the aperture or pin hole 92 in the member 94 onto the sensing elements of the light intensity detector 96.

The operation of the apparatus shown in FIG. 6 is identical to that described above for the aspect shown in FIG. 5 in so far as the controller 66 being responsive to output signals from the detector 96 to detect a light intensity matching or exceeding the predetermined threshold 32 so as to cease further exposure by the laser 62 at a predetermined point in the slot 38. The motion controllers 60 or 57 may also be used to control the speed of movement or motion of the laser beam 64, thereby controlling the exposure time of the scoring laser beam 64 on a specific spot in the sample 42.

The confocal optical measurement apparatus and method of the present invention enables a measurement of the depth of a slot scored in a material layer(s) to be determined in real time during formation of the slot. This enables immediate control to be provided to the laser to accurately control the depth of the slot and thereby to maintain the remaining thickness in the material between the bottom of the slot and the spaced outer surface of the material at a constant predetermined thickness. The present apparatus and method also accommodates irregular exterior surfaces of the outer material layer while still maintaining a constant

remaining thickness between the bottom of the slot and the outer surface of the material layer.

